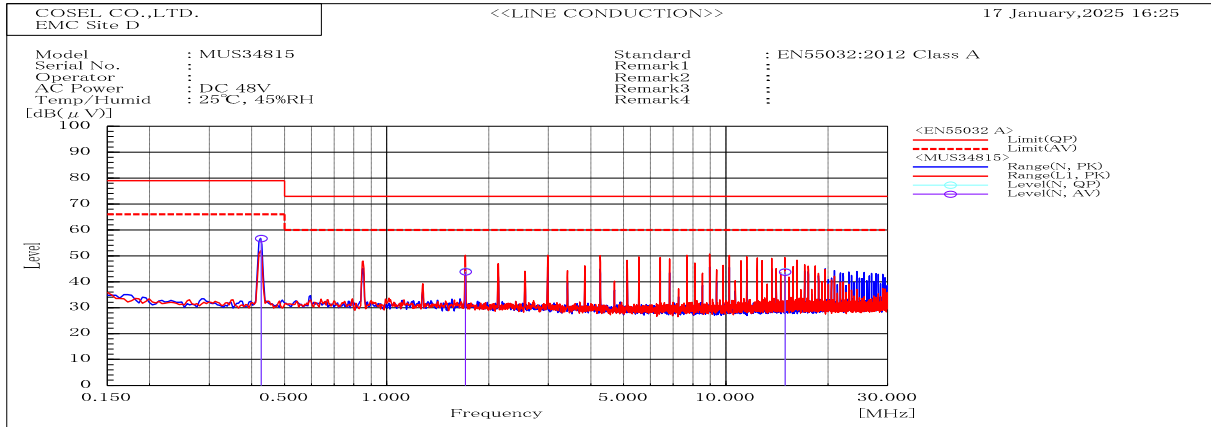
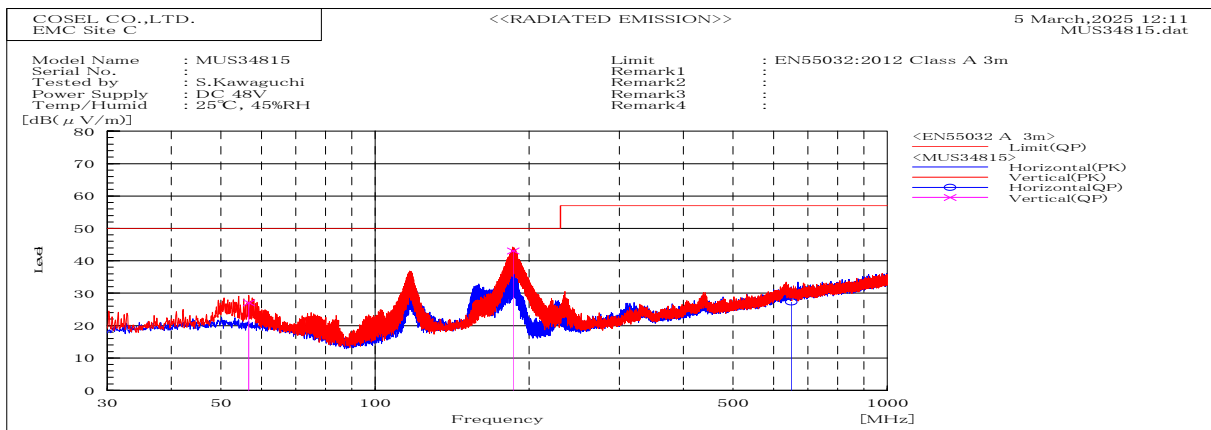


DATA SHEET		Date	05-Mar-25
Model	MUS34815	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi



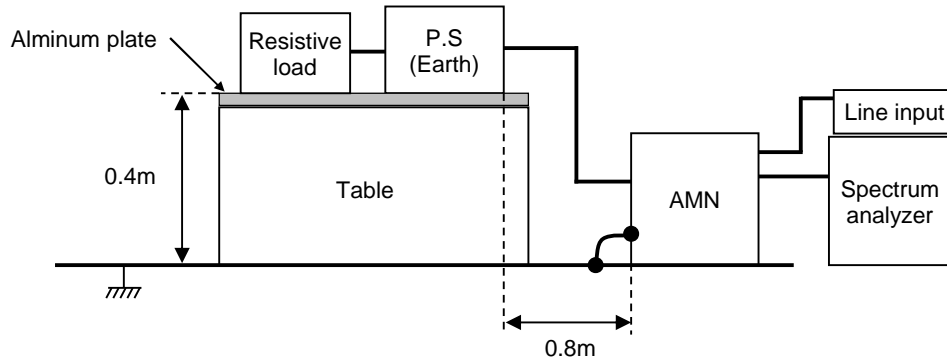
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.427	N	56.8	56.7	79	66	22.2	9.3	Pass	
1.709	N	44.1	43.8	73	60	28.9	16.2	Pass	
14.954	N	44	43.7	73	60	29	16.3	Pass	



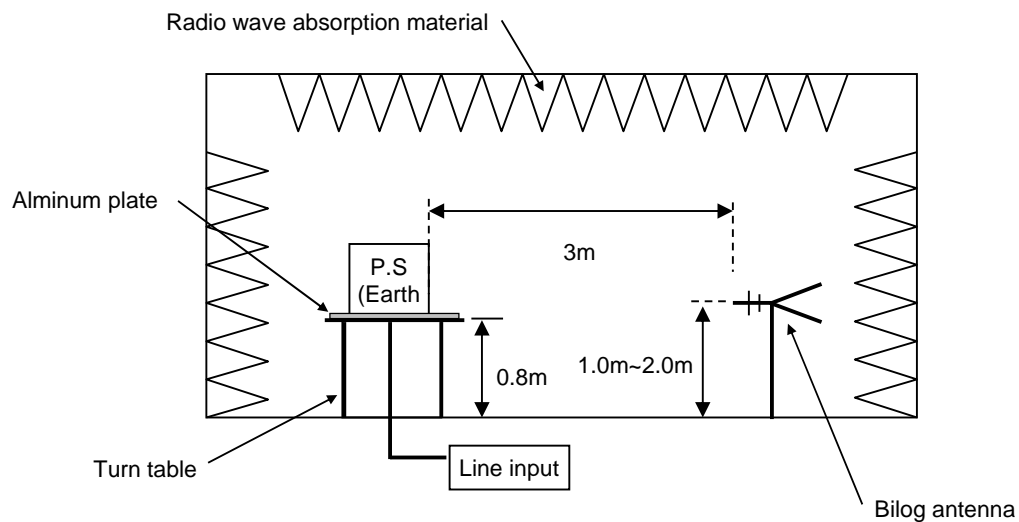
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV						
186.037	V	Stable	43.1	50	6.9	Pass	101.6	9.3		
649.943	H	Stable	27.3	57	29.7	Pass	120.2	25.2		
56.736	V	Stable	27.1	50	22.9	Pass	100.2	348.8		

DATA SHEET		Date	05-Mar-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi

### 1. Line conduction



### 2. Radiated emission



## Conditions

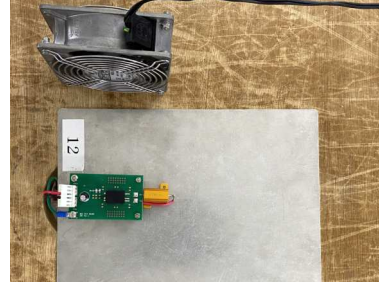
Test : EMI  
Model Name: MUS3□□

## ○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



## ○Testing circuitry

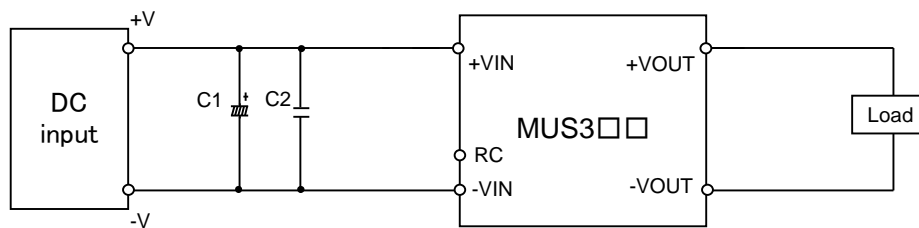


Fig.1 MUS305□, MUS312□, MUS324□ Testing circuitry

C1 :	MUS305□	16V 220 $\mu$ F	Electric capacitor (UPWseries NICHICON)
	MUS312□	50V 100 $\mu$ F	Electric capacitor (UPWseries NICHICON)
	MUS324□	-	
C2 :	MUS305□	16V 22 $\mu$ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUS312□	25V 22 $\mu$ F	Ceramic capacitor (C3216JB1E226MT TDK)
	MUS324□	50V 10 $\mu$ F	Ceramic capacitor (C3216X7R1H106KT TDK)

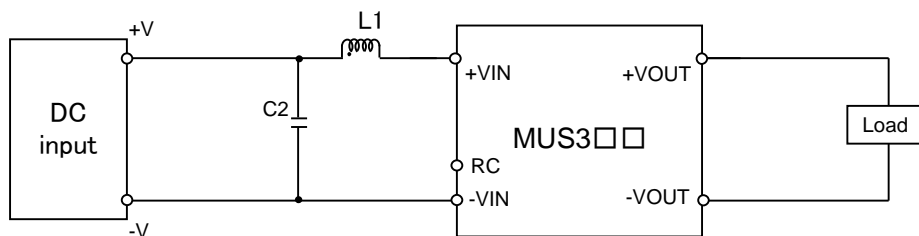


Fig.2 MUS348□ Testing circuitry

C2 :	MUS348□	100V 2.2 $\mu$ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUS348□	520mA 15 $\mu$ H	Inductor(LQH32PN150MN0L MURATA MANUFACTURING)